

<b>Notice of References Cited</b>	Application/Control No. 10/592,006		Applicant(s)/Patent Under Reexamination OHNO ET AL.	
	Examiner DANIEL WHALEN		Art Unit 2829	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,274,890 B1	08-2001	Oshio et al.	257/98
*	B	US-2002/0084518 A1	07-2002	Hasebe et al.	257/676
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 05063242 A	03-1993	Japan	FUJIWARA et al.	H01L 33/00
	O	JP 2001352100 A	12-2001	Japan	TSUTSUI, TAKESHI	H01L 33/00
	P					
	Q					
	R					
	S					
	I					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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